



PRODUCT DESCRIPTION

TOKYO ELECTRON P-12XL LABVIEW DRIVER

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FemtoTek's LabVIEW Driver for the Tokyo Electron P-12XL Prober is a software package that enables automated control of the Tokyo Electron P-12XL wafer prober. The driver software communicates with the prober through the computer's GPIB interface.

FemtoTek's driver package includes:

- TEL-P12XL command VIs
- Checkout panel
- Sample programs

The driver library offers a choice of more than forty commands (see table below). The prober responds to move and action commands by means of the GPIB SRQ. The LabVIEW driver converts the STB (status byte) information returned with the SRQ into a prober status. The prober status information can be used to create LabVIEW programs that process cassettes and wafers, and react to error conditions.

The checkout panel allows you to send a selection of commands to the prober one at a time to verify the prober and GPIB interface.

The sample programs demonstrate how to combine the prober driver with DUT test routines. For a typical application, shown in the sample programs, the operator intervenes only to load the cassette and initial wafer. The rest of the cassette can be measured automatically using computer control.

Commands implemented in the TEL-P12XL driver library

Move:	
<ul style="list-style-type: none">▪ Move x▪ Move y▪ Move xy relative▪ Move to xy index▪ Move x relative▪ Move y relative▪ Move to reference die	<ul style="list-style-type: none">▪ Move to next die▪ Fail move to next die▪ Z up▪ Z down▪ Z-axis adjust
Action:	
<ul style="list-style-type: none">▪ Load wafer▪ Unload wafer▪ Unload reject wafer	<ul style="list-style-type: none">▪ Send test start TTL▪ Release manual test▪ Polish needle

<ul style="list-style-type: none"> ▪ Stop with buzzer on ▪ Set contact position ▪ Ink ▪ Drive selected inker 	<ul style="list-style-type: none"> ▪ Brush needle ▪ Polish and brush needle ▪ Print text
<p>Setting & Configuration:</p> <ul style="list-style-type: none"> ▪ Set pass fail bin ▪ Set pass fail ▪ Set wafer name ▪ Set hot chuck temperature ▪ Set lot parameter 	
<p>Status Query:</p> <ul style="list-style-type: none"> ▪ Get xy coordinates ▪ Get xy reference ▪ Get on wafer ▪ Get pass fail count ▪ Get wafer id ▪ Get machine number ▪ Get hot chuck temperature ▪ Get hot chuck setpoint ▪ Get lot parameter ▪ Get multi-test parameters ▪ Get needle polish ▪ Get wafer parameter ▪ Get cassette map ▪ Get cassette status ▪ Read error code 	
<p>General:</p> <ul style="list-style-type: none"> ▪ Initialize ▪ Close 	